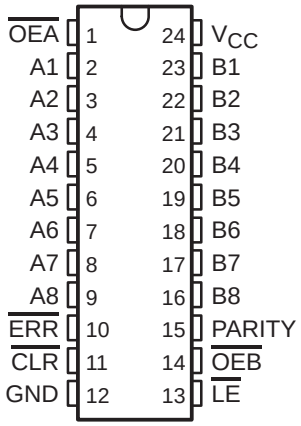
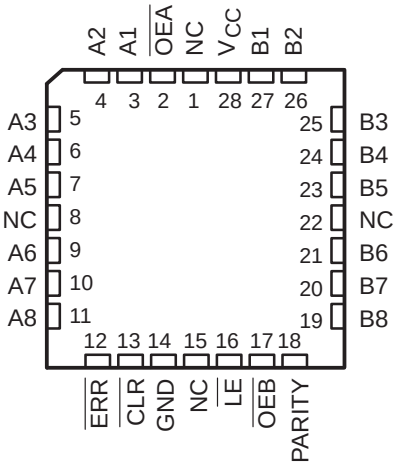
- **State-of-the-Art *EPIC*-II*B*™ BiCMOS Design Significantly Reduces Power Dissipation**
- **ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Latch-Up Performance Exceeds 500 mA Per JESD 17**
- **Typical V_{OLP} (Output Ground Bounce) < 1 V at V_{CC} = 5 V, T_A = 25°C**
- **High-Drive Outputs (–32-mA I_{OH}, 64-mA I_{OL})**
- **High-Impedance State During Power Up and Power Down**
- **Parity-Error Flag With Parity Generator/Checker**
- **Latch for Storage of Parity-Error Flag**
- **Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK), Ceramic Flat (W) Package, and Plastic (NT) and Ceramic (JT) DIPs**

SN54ABT853 . . . JT OR W PACKAGE
SN74ABT853 . . . DB, DW, NT, OR PW PACKAGE
(TOP VIEW)



SN54ABT853 . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection

description

The ’ABT853 8-bit to 9-bit parity transceivers are designed for communication between data buses. When data is transmitted from the A bus to the B bus, a parity bit is generated. When data is transmitted from the B bus to the A bus with its corresponding parity bit, the open-collector parity-error ($\overline{ERR}$) output indicates whether or not an error in the B data has occurred. The output-enable ($\overline{OEA}$ and $\overline{OEB}$) inputs can be used to disable the device so that the buses are effectively isolated. The ’ABT853 transceivers provide true data at their outputs.

A 9-bit parity generator/checker generates a parity-odd (PARITY) output and monitors the parity of the I/O ports with the $\overline{ERR}$ flag. The parity-error output can be passed, sampled, stored, or cleared from the latch using the latch-enable ($\overline{LE}$) and clear ($\overline{CLR}$) control inputs. When both $\overline{OEA}$ and $\overline{OEB}$ are low, data is transferred from the A bus to the B bus and inverted parity is generated. Inverted parity is a forced error condition that gives the designer more system diagnostic capability.

When V_{CC} is between 0 and 2.1 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 2.1 V, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

description (continued)

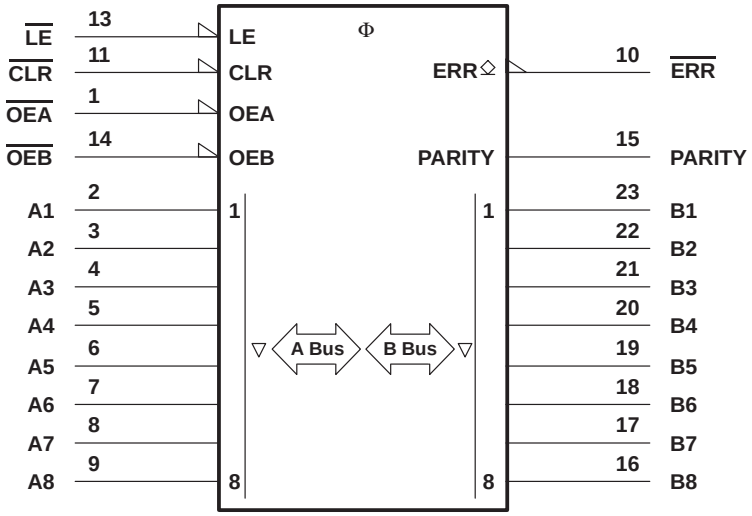
The SN54ABT853 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ABT853 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE

INPUTS						OUTPUTS AND I/Os				FUNCTION
$\overline{OEB}$	$\overline{OEA}$	$\overline{CLR}$	LE	Ai Σ OF H	Bi† Σ OF H	A	B	PARITY	$\overline{ERR}$‡	
L	H	X	X	Odd Even	NA	NA	A	L H	NA	A data to B bus and generate parity
H	L	X	L	NA	Odd Even	B	NA	NA	H L	B data to A bus and check parity
H	L	H	H	NA	X	X	NA	NA	NC	Store error flag
X	X	L	H	X	X	X	NA	NA	H	Clear error flag register
H	H	H L X X	H H L L	X X L Odd H Even	X	Z	Z	Z	NC H H L	Isolation§ (parity check)
L	L	X	X	Odd Even	NA	NA	A	H L	NA	A data to B bus and generate inverted parity

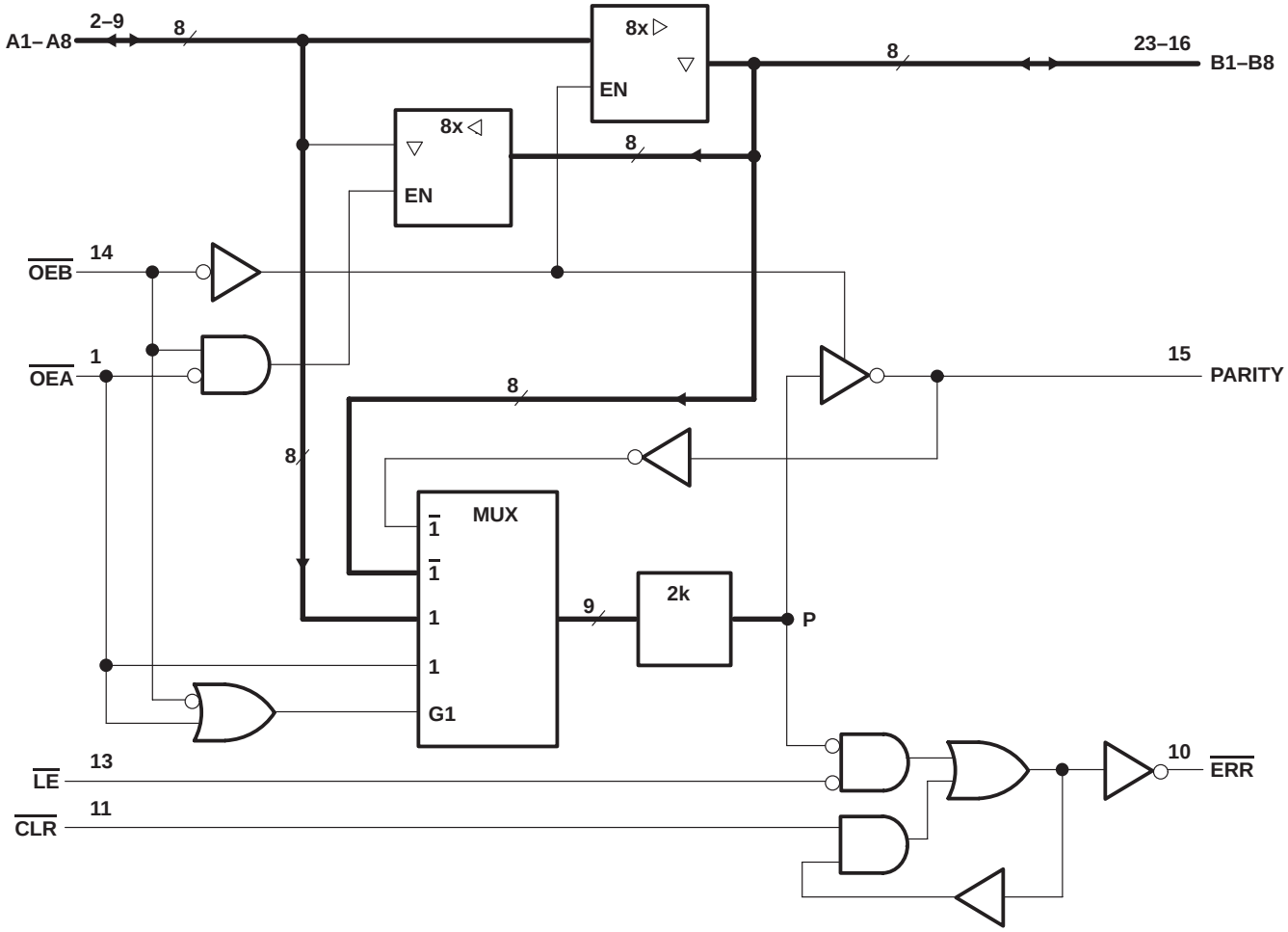
NA = not applicable, NC = no change, X = don't care
† Summation of high-level inputs includes PARITY along with Bi inputs.
‡ Output states shown assume $\overline{ERR}$ was previously high.
§ In this mode, $\overline{ERR}$ (when clocked) shows inverted parity of the A bus.

logic symbol¶



¶ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for the DB, DW, JT, NT, PW, and W packages.

logic diagram (positive logic)



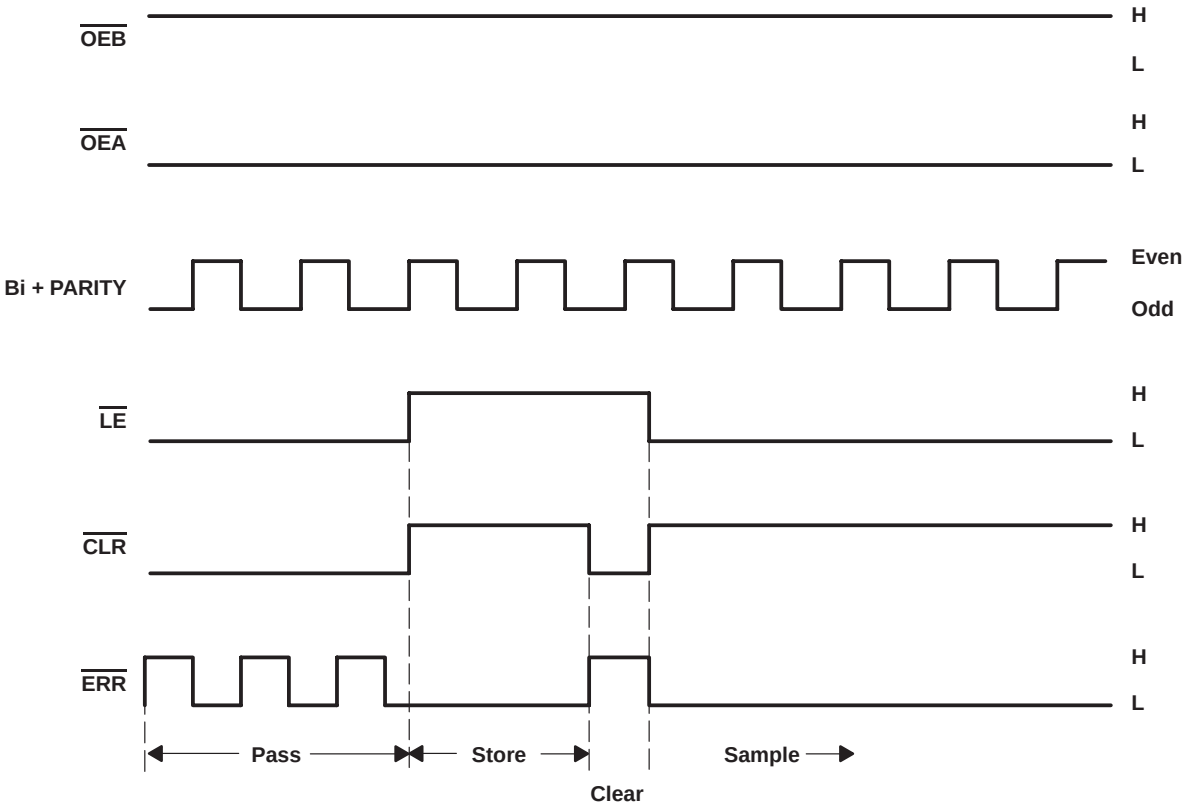
Pin numbers shown are for the DB, DW, JT, NT, PW, and W packages.

ERROR-FLAG FUNCTION TABLE

INPUTS		INTERNAL TO DEVICE	OUTPUT PRESTATE	OUTPUT $\overline{ERR}$	FUNCTION
$\overline{CLR}$	LE	POINT P	$\overline{ERR}_{N-1}$†		
L	L	L	X	L	Pass
		H		H	
H	L	L	X	L	Sample
		X	L	L	
		H	H	H	
L	H	X	X	H	Clear
H	H	X	L	L	Store
			H	H	

† The state of $\overline{ERR}$ before changes at $\overline{CLR}$, $\overline{LE}$, or point P

error-flag waveforms



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC} . . . . . –0.5 V to 7 V
Input voltage range, V_I: Except I/O ports (see Note 1) . . . . . –0.5 V to 7 V
Voltage range applied to any output in the high or power-off state, V_O . . . . . –0.5 V to 5.5 V
Current into any output in the low state, I_O: SN54ABT853 . . . . . 96 mA
SN74ABT853 . . . . . 128 mA
Input clamp current, I_{IK} (V_I < 0) . . . . . –18 mA
Output clamp current, I_{OK} (V_O < 0) . . . . . –50 mA
Package thermal impedance, θ_{JA} (see Note 2): DB package . . . . . 104°C/W
DW package . . . . . 81°C/W
N package . . . . . 67°C/W
PW package . . . . . 120°C/W
Storage temperature range, T_{stg} . . . . . –65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions (see Note 3)

			SN54ABT853		SN74ABT853		UNIT
			MIN	MAX	MIN	MAX	
V_{CC}	Supply voltage		4.5	5.5	4.5	5.5	V
V_{IH}	High-level input voltage		2		2		V
V_{IL}	Low-level input voltage			0.8		0.8	V
V_I	Input voltage		0	V_{CC}	0	V_{CC}	V
V_{OH}	High-level output voltage	$\overline{ERR}$		5.5		5.5	V
I_{OH}	High-level output current	Except $\overline{ERR}$		–24		–32	mA
I_{OL}	Low-level output current			48		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	Outputs enabled		10		10	ns/V
$\Delta t/\Delta V_{CC}$	Power-up ramp rate		200		200		μs/V
T_A	Operating free-air temperature		–55	125	–40	85	°C

NOTE 3: Unused pins (input or I/O) must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		T_A = 25°C			SN54ABT853		SN74ABT853		UNIT
				MIN	TYP†	MAX	MIN	MAX	MIN	MAX	
V_{IK}		V_{CC} = 4.5 V,	I_I = –18 mA			–1.2		–1.2		–1.2	V
V_{OH}	All outputs except $\overline{ERR}$	V_{CC} = 4.5 V,	I_{OH} = –3 mA	2.5			2.5		2.5		V
		V_{CC} = 5 V,	I_{OH} = –3 mA	3			3		3		
		V_{CC} = 4.5 V	I_{OH} = –24 mA	2			2				
			I_{OH} = –32 mA	2*					2		
V_{OL}		V_{CC} = 4.5 V	I_{OL} = 24 mA			0.55		0.55			V
			I_{OL} = 64 mA			0.55*				0.55	
V_{hys}					100						mV
I_{OH}	$\overline{ERR}$	V_{CC} = 4.5 V,	V_{OH} = 5.5 V			50		50		50	µA
I_I	Control inputs	V_{CC} = 5.5 V,	V_I = V_{CC} or GND			±1		±1		±1	µA
	A or B ports					±100		±100		±100	
I_{OZPU}‡		V_{CC} = 0 to 2.1 V, V_O = 0.5 V to 2.7 V, $\overline{OE}$ = X				±50		±50		±50	µA
I_{OZPD}‡		V_{CC} = 2.1 V to 0, V_O = 0.5 V to 2.7 V, $\overline{OE}$ = X				±50		±50		±50	µA
I_{OZH}§		V_{CC} = 5.5 V,	V_O = 2.7 V			10		10		10	µA
I_{OZL}§		V_{CC} = 5.5 V,	V_O = 0.5 V			–10		–10		–10	µA
I_{off}		V_{CC} = 0,	V_I or V_O ≤ 4.5 V			±100				±100	µA
I_{CEX}		V_{CC} = 5.5 V, V_O = 5.5 V	Outputs high			50		50		50	µA
I_O¶		V_{CC} = 5.5 V,	V_O = 2.5 V	–50	–100	–200#	–50	–200#	–50	–200#	mA
I_{CC}	A or B ports	V_{CC} = 5.5 V, I_O = 0, V_I = V_{CC} or GND	Outputs high		1	250		450		250	µA
			Outputs low		24	38		38		38	mA
			Outputs disabled		0.5	250		450		250	µA
ΔI_{CC}‖	Data inputs	V_{CC} = 5.5 V, One input at 3.4 V, Other inputs at V_{CC} or GND	Outputs enabled			1.5		1.5		1.5	mA
			Outputs disabled			50		50		50	µA
	Control inputs	V_{CC} = 5.5 V, One input at 3.4 V, Other inputs at V_{CC} or GND				1.5		1.5		1.5	mA
C_i	Control inputs	V_I = 2.5 V or 0.5 V			4.5						pF
C_{io}	A or B ports	V_O = 2.5 V or 0.5 V			10.5						pF

* On products compliant to MIL-PRF-38535, this parameter does not apply.
† All typical values are at V_{CC} = 5 V.
‡ This parameter is characterized, but not production tested.
§ The parameters I_{OZH} and I_{OZL} include the input leakage current.
¶ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
# This data sheet limit can vary among suppliers.
‖ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

			V_{CC} = 5 V, T_A = 25°C		SN54ABT853		SN74ABT853		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
t_w	Pulse duration	$\overline{LE}$ high or low	3.5		3.5		3.5		ns
		$\overline{CLR}$ low	4		4		4		
t_{su}	Setup time	B or PARITY before $\overline{LE}\downarrow$	9.4†		10.2		9.4†		ns
		$\overline{CLR}$ before $\overline{LE}\downarrow$	2		2		2		
t_h	Hold time	B or PARITY after $\overline{LE}\downarrow$	0		0		0		ns
		$\overline{CLR}$ after $\overline{LE}\downarrow$	3		3		3		

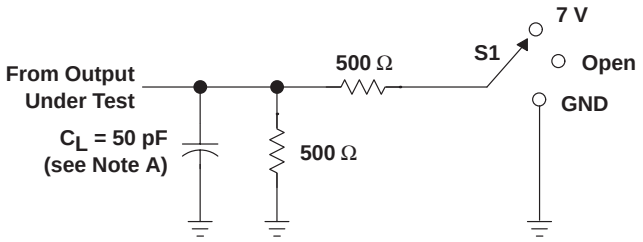
† This data sheet limit can vary among suppliers.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 5 V, T_A = 25°C			SN54ABT853		SN74ABT853		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{PLH}	A or B	B or A	1.2		4.8	1.2	6.4	1.2	5.3	ns
t_{PHL}			1		4.8†	1	5.4	1	5.3†	
t_{PLH}	A	PARITY	2.1		9.5	2.1	13.3	2.1	11.2	ns
t_{PHL}			2.5		9.7	2.5	11	2.5	11	
t_{PLH}	$\overline{OE}$	PARITY	1.8		8.5	1.8	13.6	1.8	10.5	ns
t_{PHL}			2.3		8.6	2.3	11.7	2.3	10	
t_{PLH}	$\overline{CLR}$	$\overline{ERR}$	1		5.5	1	6.3	1	6.2	ns
t_{PLH}	$\overline{LE}$	ERR	1.8		5.1	1.8	6.1	1.8	6	ns
t_{PHL}			1†		5.8	1†	6.7	1	6.6	
t_{PLH}	B or PARITY	ERR	2		10.1	2	11.8	2	11.7	ns
t_{PHL}			2.2†		11.5	2.2†	12.9	2.2†	12.8	
t_{PZH}	$\overline{OE}$	A or B or PARITY	1		5.8†	1	8.8	1	6.7†	ns
t_{PZL}			1.5†		5.8	1.5†	9.8	1.5†	6.7	
t_{PHZ}	$\overline{OE}$	A or B or PARITY	1.8†		7.3	1.8†	9.5	1.8†	7.9	ns
t_{PLZ}			2.1†		7.2	2.1†	8.2	2.1†	8.1	

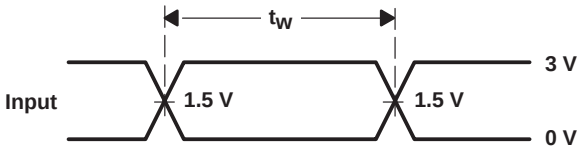
† This data sheet limit can vary among suppliers.

PARAMETER MEASUREMENT INFORMATION

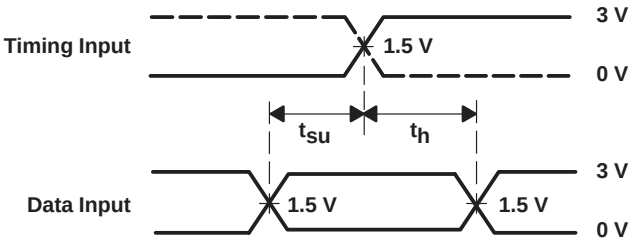


TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	7 V
t_{PHZ}/t_{PZH}	Open

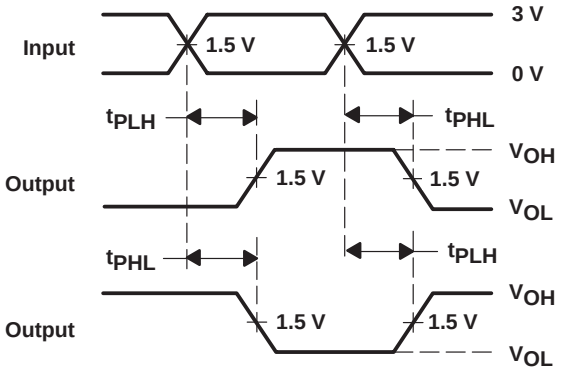
LOAD CIRCUIT



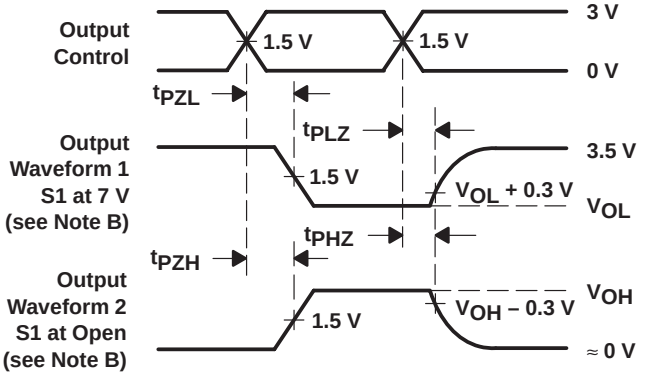
VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES
INVERTING AND NONINVERTING OUTPUTS



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES
LOW- AND HIGH-LEVEL ENABLING

NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

SN54ABT853, 8-Bit To 9-Bit Parity Bus Transceivers

DEVICE STATUS: **ACTIVE**

PARAMETER NAME	SN54ABT853	SN74ABT853
Voltage Nodes (V)	5	5
Vcc range (V)	4.5 to 5.5	4.5 to 5.5
Input Level	TTL	TTL
Output Level	TTL	TTL
Output Drive (mA)		-32/64
No. of Outputs	8	8
Logic	True	True
Static Current		19.12
tpd max (ns)		5.3

FEATURES

Back to Top

- State-of-the-Art ***EPIC***-II ***B***™ BiCMOS Design Significantly Reduces Power Dissipation
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 500 mA Per JESD 17
- Typical V_{OLP} (Output Ground Bounce) < 1 V at V_{CC} = 5 V, T_A = 25°C
- High-Drive Outputs (-32-mA I_{OH}, 64-mA I_{OL})
- High-Impedance State During Power Up and Power Down
- Parity-Error Flag With Parity Generator/Checker
- Latch for Storage of Parity-Error Flag
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK), Ceramic Flat (W) Package, and Plastic (NT) and Ceramic (JT) DIPs

DESCRIPTION

Back to Top

The 'ABT853 8-bit to 9-bit parity transceivers are designed for communication between data buses. When data is transmitted from the A bus to the B bus, a parity bit is generated. When data is transmitted from the B bus to the A bus with its corresponding parity bit, the open-collector parity-error (ERR\) output indicates whether or not an error in the B data has occurred. The output-enable (OEA\ and OEB\) inputs can be used to disable the device so that the buses are effectively isolated. The 'ABT853 transceivers provide true data at their outputs.

A 9-bit parity generator/checker generates a parity-odd (PARITY) output and monitors the parity of the I/O ports with the ERR\ flag. The parity-error output can be passed, sampled, stored, or cleared from the latch using the latch-enable (LE\) and clear (CLR\) control inputs. When both OEA\ and OEB\ are low, data is transferred from the A bus to the B bus and inverted parity is generated. Inverted parity is a forced error condition that gives the designer more system diagnostic capability.

When V_{CC} is between 0 and 2.1 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 2.1 V, OE\ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

TECHNICAL DOCUMENTS

Back to Top

To view the following documents, Acrobat Reader 4.0 is required.

To download a document to your hard drive, right-click on the link and choose 'Save'.

Product Folder: SN54ABT853, 8-Bit To 9-Bit Parity Bus Transceivers

DATASHEET

Back to Top

Full datasheet in Acrobat PDF: sn54abt853.pdf (140 KB,Rev.F) (Updated: 10/01/1997)

APPLICATION NOTES

Back to Top

View Application Notes for Digital Logic

- Advanced BiCMOS Technology (ABT) Logic Characterization Information (Rev. B) (SCBA008B - Updated: 06/01/1997)
- Advanced BiCMOS Technology (ABT) Logic Enables Optimal System Design (Rev. A) (SCBA001A - Updated: 03/01/1997)
- Bus-Interface Devices With Output-Damping Resistors Or Reduced-Drive Outputs (Rev. A) (SCBA012A - Updated: 08/01/1997)
- Designing With Logic (Rev. C) (SDYA009C - Updated: 06/01/1997)
- Evaluation of Nickel/Palladium/Gold-Finished Surface-Mount Integrated Circuits (SZZA026 - Updated: 06/20/2001)
- Family of Curves Demonstrating Output Skews for Advanced BiCMOS Devices (Rev. A) (SCBA006A - Updated: 12/01/1996)
- Implications of Slow or Floating CMOS Inputs (Rev. C) (SCBA004C - Updated: 02/01/1998)
- Input and Output Characteristics of Digital Integrated Circuits (SDYA010 - Updated: 10/01/1996)
- Live Insertion (SDYA012 - Updated: 10/01/1996)
- Power-Up 3-State (PU3S) Circuits in TI Standard Logic Devices (SZZA033 - Updated: 05/10/2002)
- Quad Flatpack No-Lead Logic Packages (Rev. C) (SCBA017C - Updated: 11/22/2002)
- TI IBIS File Creation, Validation, and Distribution Processes (SZZA034 - Updated: 08/29/2002)
- Understanding Advanced Bus-Interface Products Design Guide (SCAA029, 253 KB - Updated: 05/01/1996)
- Understanding and Interpreting Texas Instruments Standard-Logic Products Data Sh (Rev. A) (SZZA036A - Updated: 02/27/2003)

MORE LITERATURE

Back to Top

- Enhanced Plastic Portfolio Brochure (SGZB004, 387 KB - Updated: 08/19/2002)
- Logic Reference Guide (SCYB004, 1032 KB - Updated: 10/23/2001)
- MicroStar Junior BGA Design Summary (SCET004, 167 KB - Updated: 07/28/2000)
- Military Brief (SGYN138, 803 KB - Updated: 10/10/2000)
- Overview of IEEE Std 91-1984, Explanation of Logic Symbols Training Booklet (Rev. A) (SDYZ001A, 138 KB - Updated: 07/01/1996)
- Palladium Lead Finish User's Manual (SDYV001, 2041 KB - Updated: 11/01/1996)
- QML Class V Space Products Military Brief (Rev. A) (SGZN001A, 257 KB - Updated: 10/07/2002)

USER GUIDES

Back to Top

- LOGIC Pocket Data Book (SCYD013, 4837 KB - Updated: 12/05/2002)

PRICING/AVAILABILITY/PKG

Back to Top

DEVICE INFORMATION
Updated Daily

ORDERABLE DEVICE	STATUS	PACKAGE TYPE | PINS	TEMP (°C)	DSCC NUMBER	PRODUCT CONTENT	BUDGETARY PRICING QTY | $US	STD PACK QTY
5962-9674601Q3A	ACTIVE	LCCC (FK) | 28	-55 TO 125		View Contents	1KU | 19.22	1
5962-9674601QKA	ACTIVE	CFP (W) | 24	-55 TO 125		View Contents	1KU | 16.47	1
5962-9674601QLA	ACTIVE	CDIP (JT) | 24	-55 TO 125		View Contents	1KU | 10.98	1
SNJ54ABT853FK	ACTIVE	LCCC (FK) | 28	-55 TO 125	5962-9674601Q3A	View Contents	1KU | 19.22	1

TI INVENTORY STATUS
As Of 09:00 AM GMT, 17 Apr 2003

IN STOCK	IN PROGRESS QTY | DATE	LEAD TIME
0*	3080 | 20 May	8 WKS
0*	3273 | 20 May	8 WKS
0*	3350 | 20 May	8 WKS
112*	3388 | 20 May	8 WKS

REPORTED DISTRIBUTOR INVENTORY
As Of 09:00 AM GMT, 17 Apr 2003

DISTRIBUTOR COMPANY | REGION	IN STOCK	PURCHASE
None Reported View Distributors		
None Reported View Distributors		
None Reported View Distributors		
EBV Electronik | Europe	84	BUY NOW

Product Folder: SN54ABT853, 8-Bit To 9-Bit Parity Bus Transceivers

SNJ54ABT853JT	ACTIVE	CDIP (JT)	24	-55 TO 125	5962-9674601QLA	View Contents	1KU	10.98	1	269*	2657 | 20 May	8 WKS	None Reported View Distributors
SNJ54ABT853W	ACTIVE	CFP (W)	24	-55 TO 125	5962-9674601QKA	View Contents	1KU	16.47	1	15*	3350 | 20 May	8 WKS	None Reported View Distributors

Table Data Updated on: 4/17/2003